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"Formalism to Assess the Entropy and Reliability of Loop PUF"

Jean-Luc Danger^{1,2}

Olivier Rioul¹

Sylvain Guilley^{1,2}

Alexander Schaub¹

¹ Télécom ParisTech, LTCI, UPSAY

² Secure-IC



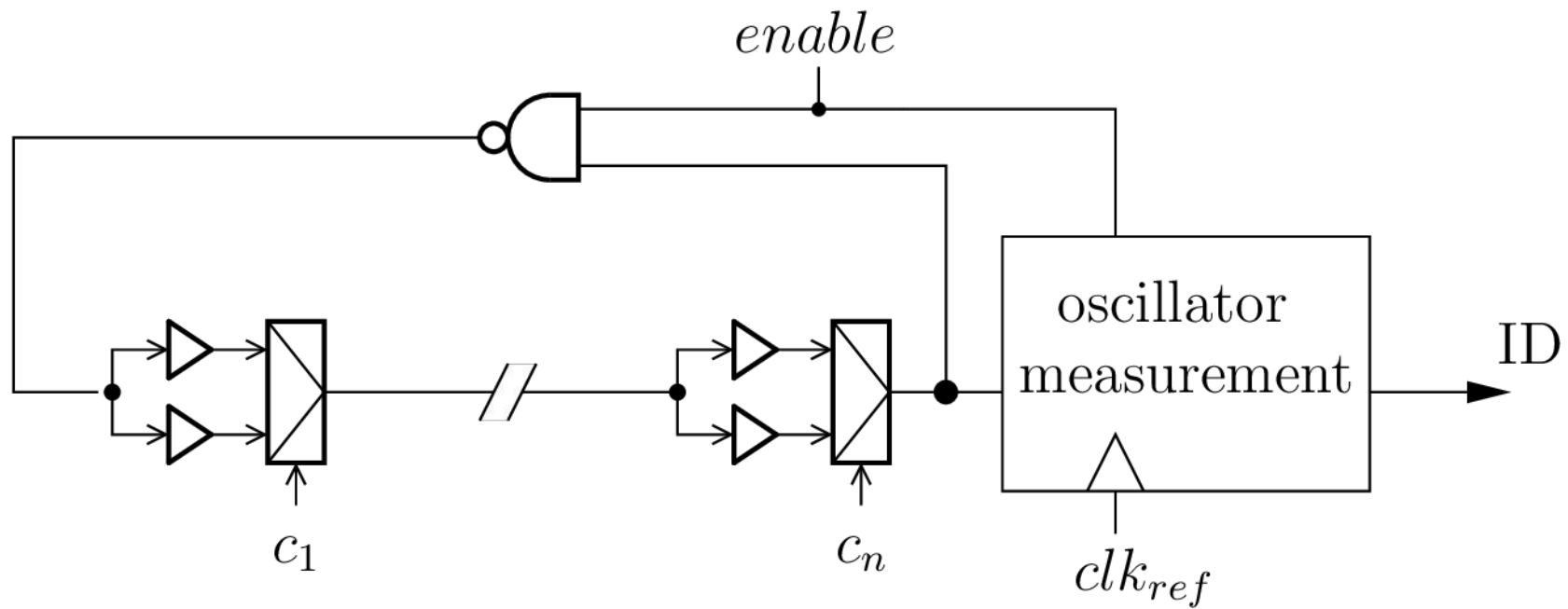


Outline

- Loop PUF architecture
- Entropy assessment
- Reliability assessment
- Results on real silicon
- Conclusions

* Depends on algorithm, not implementation

Loop PUF architecture



Operating Mode

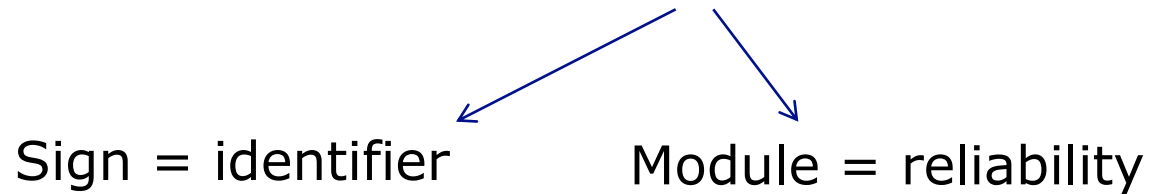
Algorithm 2.1 Operating Mode with 2 complementary challenges

Input: Challenge C (a word of n bits)

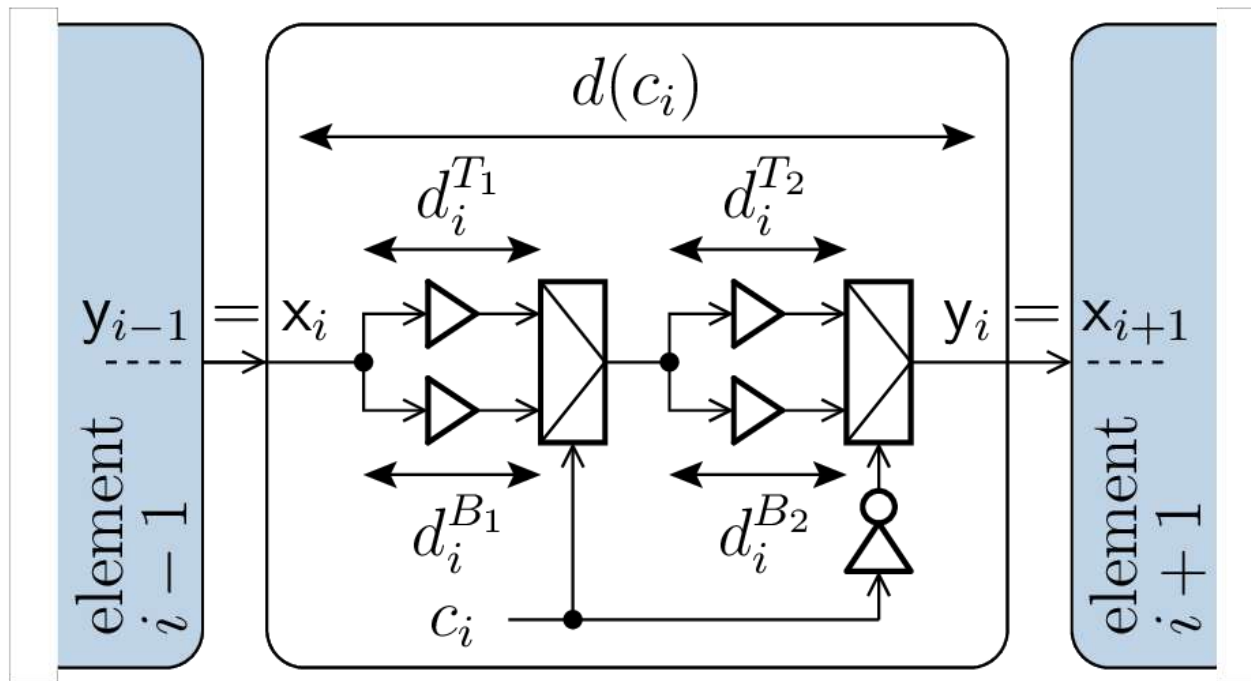
Output: Response B

- 1: Set challenge C
 - 2: Measure $d_C \leftarrow \lfloor L \sum_{i=1}^n d(c_i) \rfloor$
 - 3: Set challenge $\neg C$
 - 4: Measure $d_{\neg C} \leftarrow \lfloor L \sum_{i=1}^n d(\neg c_i) \rfloor$
 - 5: Compute $\Delta = d_C - d_{\neg C}$
 - 6: Return $B = \text{sign}(\Delta) \in \{\pm 1\}$
-

The information for each challenge is Δ

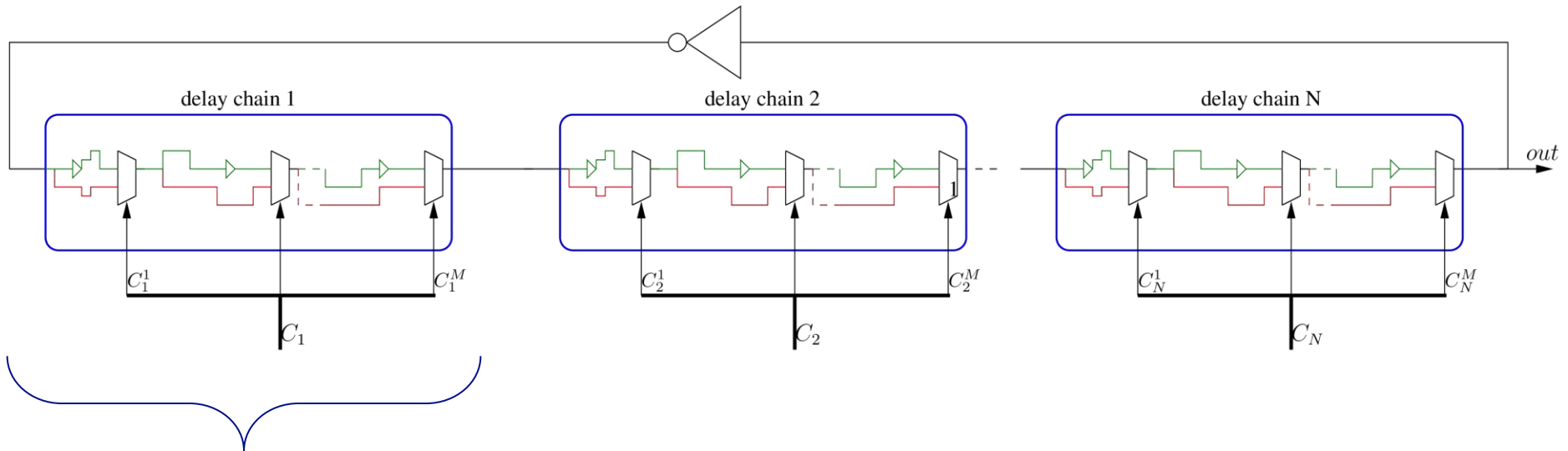


Balance of Delay Elements in ASIC



duplication

Balance of Delay Elements in FPGA



Cluster 1

Cluster 2

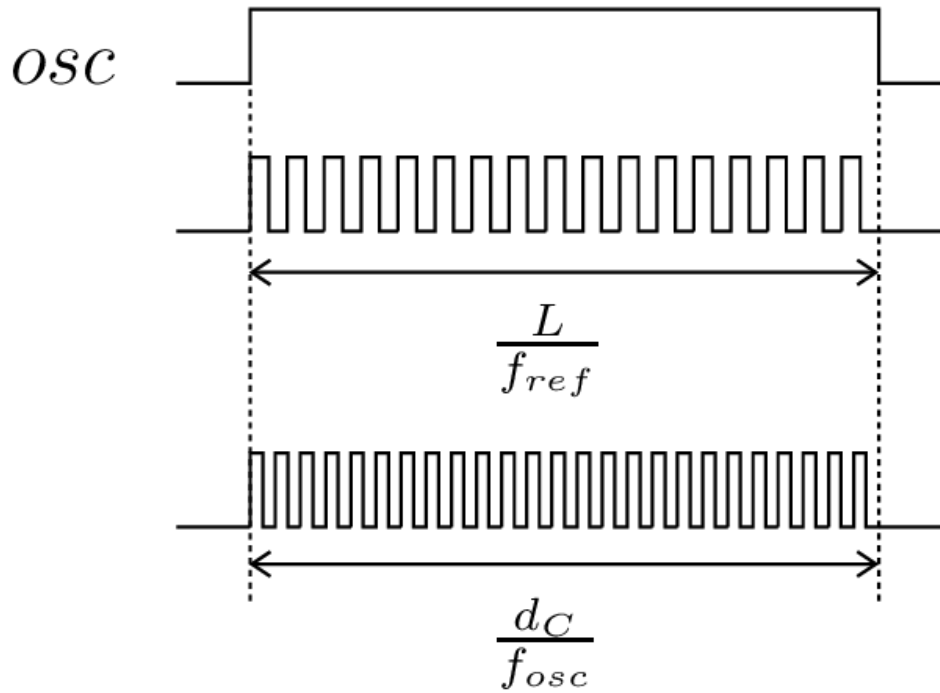
Cluster N



duplication

N duplications

Delay measurement



$$d_C = L \cdot \frac{f_{osc}}{f_{ref}}$$

Entropy

□ For a n-delay LPUF

- If challenge = Hadamard codeword of n bits => Entropy = n *

For instance for $n = 12$, the n by n Hadamard Matrix is:

$$C_{12} = \begin{pmatrix} 1 & 1 & 1 & 1 & 1 & 1 & 1 & 1 & 1 & 1 & 1 & 1 \\ 1 & 1 & 1 & 1 & 1 & 1 & -1 & -1 & -1 & -1 & -1 & -1 \\ 1 & 1 & 1 & -1 & -1 & -1 & 1 & 1 & 1 & -1 & -1 & -1 \\ 1 & 1 & -1 & 1 & -1 & -1 & 1 & -1 & -1 & 1 & 1 & -1 \\ 1 & 1 & -1 & -1 & 1 & -1 & -1 & 1 & -1 & 1 & -1 & 1 \\ 1 & 1 & -1 & -1 & -1 & 1 & -1 & -1 & 1 & -1 & 1 & 1 \\ 1 & -1 & -1 & -1 & 1 & 1 & 1 & 1 & -1 & -1 & 1 & -1 \\ 1 & -1 & 1 & 1 & -1 & -1 & -1 & 1 & -1 & -1 & 1 & 1 \\ 1 & -1 & 1 & -1 & -1 & 1 & 1 & -1 & -1 & 1 & -1 & 1 \\ 1 & -1 & -1 & 1 & -1 & 1 & -1 & 1 & 1 & 1 & -1 & -1 \\ 1 & -1 & -1 & 1 & 1 & -1 & 1 & -1 & 1 & -1 & -1 & 1 \\ 1 & -1 & 1 & -1 & 1 & -1 & -1 & -1 & 1 & 1 & 1 & -1 \end{pmatrix}$$

* Rioul, O., Solé, P., Guilley, S., & Danger, J. L. (2016, July). On the Entropy of Physically Unclonable Functions. In *Information Theory (ISIT), 2016 IEEE International Symposium on* (pp. 2928-2932). IEEE.

Entropy with more than n challenges

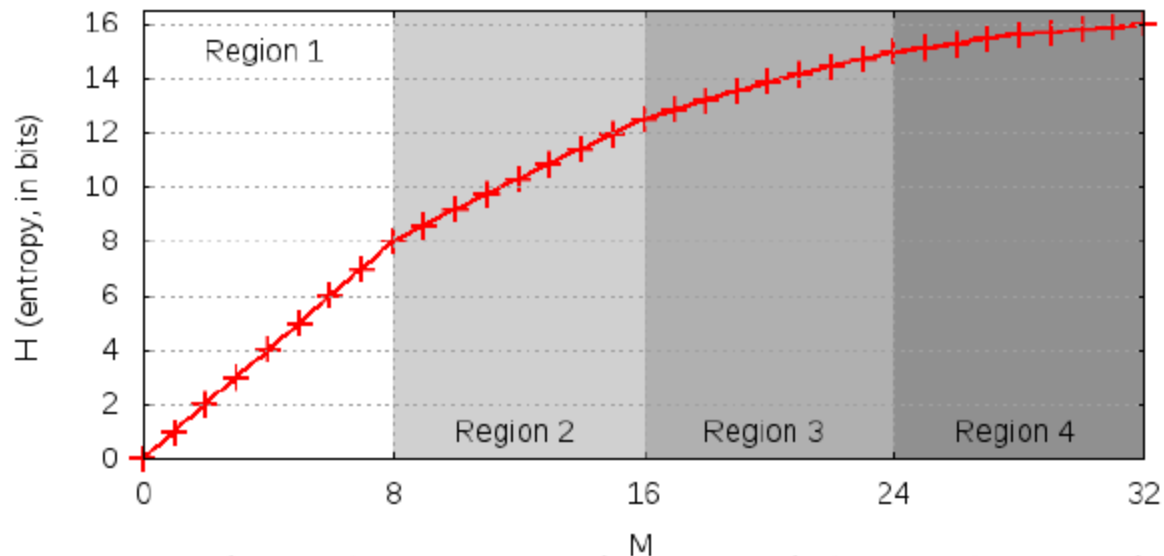


Figure 4: Entropy for n elements as a function of the number M of challenges.

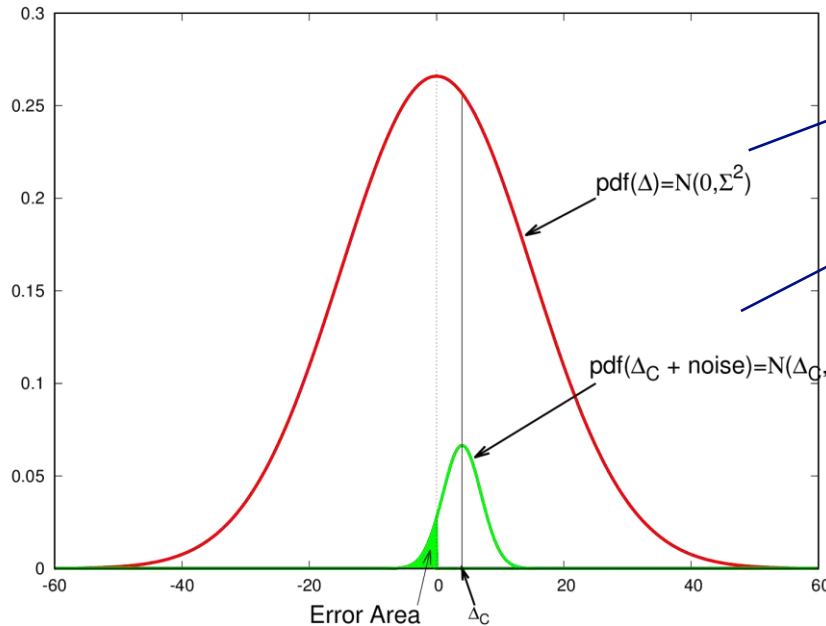
LPUF reliability

$$BER = \mathbb{P}(\text{sign}(\Delta + N) \neq \text{sign}(\Delta)) = Q\left(\frac{|\Delta|}{\sigma}\right)$$

$$N \sim \mathcal{N}(0, \sigma^2)$$

$$Q(x) = \frac{1}{2}(1 - \text{erf} \frac{x}{\sqrt{2}}) = \frac{1}{2} \text{erfc}(\frac{x}{\sqrt{2}})$$

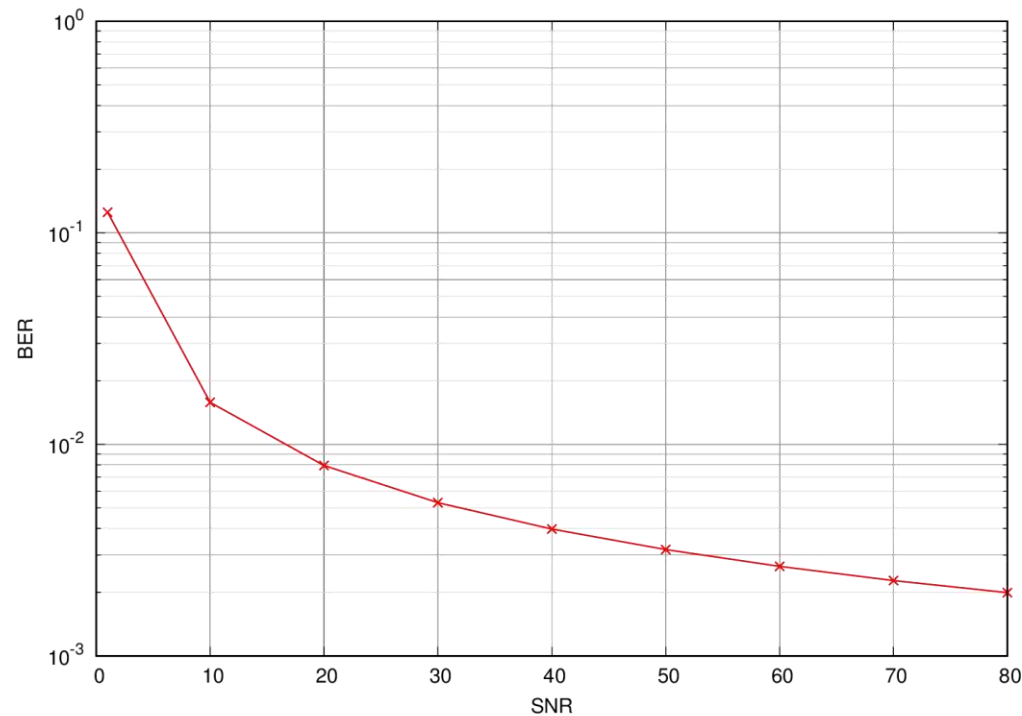
$$\widehat{BER} = \int_0^{+\infty} \mathbb{P}(\Delta) \cdot BER(\Delta) \cdot d\Delta$$



With $SNR = \frac{\Sigma}{\sigma}$

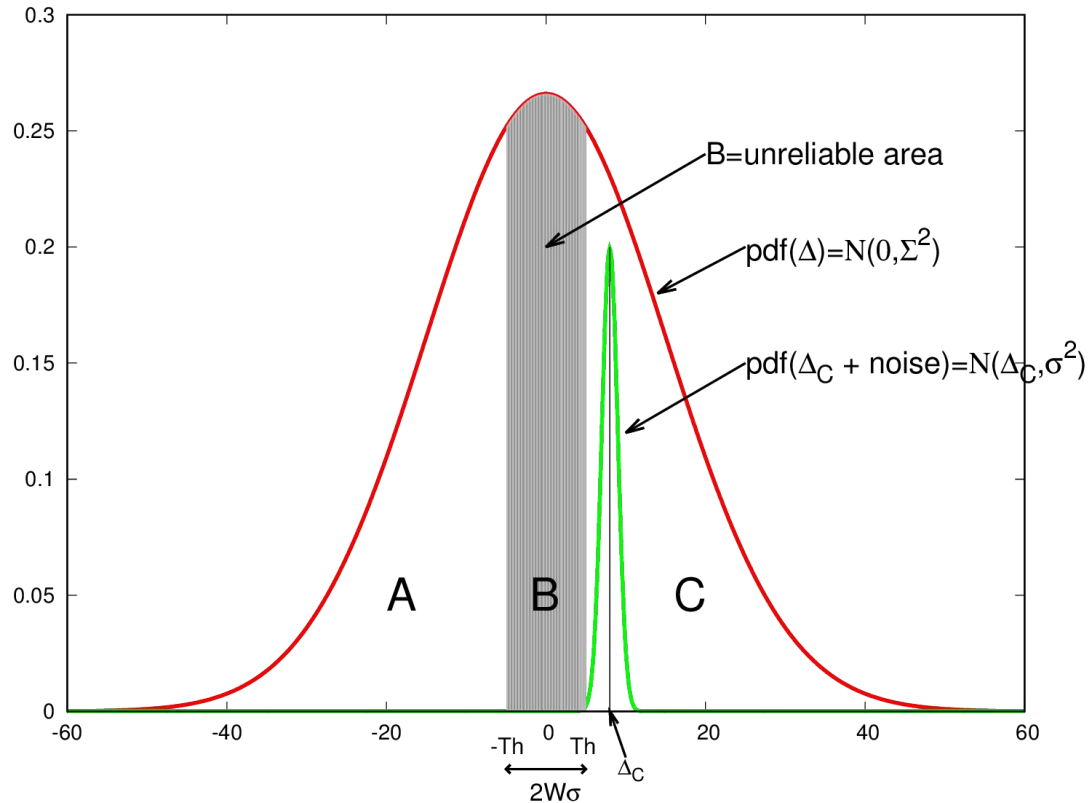
$$\widehat{BER} = \frac{1}{4} - \frac{1}{2\pi} \arctan(SNR)$$

LPUF reliability



The Reliability is not enough $\sim 10^{-3}$ even with high SNR
=> Needs of secure sketch : Error Correcting codes and Helper data

Reliability enhancement by delay knowledge



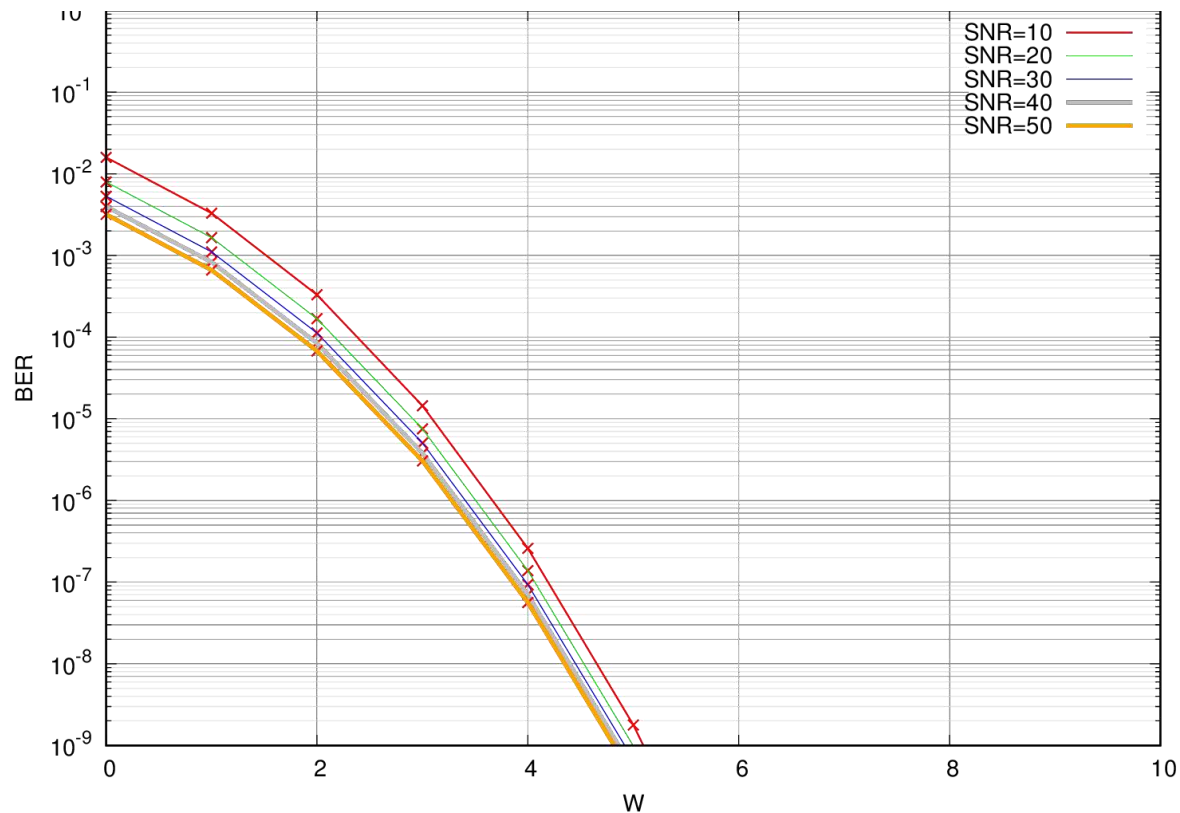
Bit unreliable \Leftrightarrow
 $|\text{delay}| < Th$

$$Th = W\sigma$$

The bits in the unreliable area "B" are discarded
The helper data indicates the unreliable bits

New BER with filtered bits

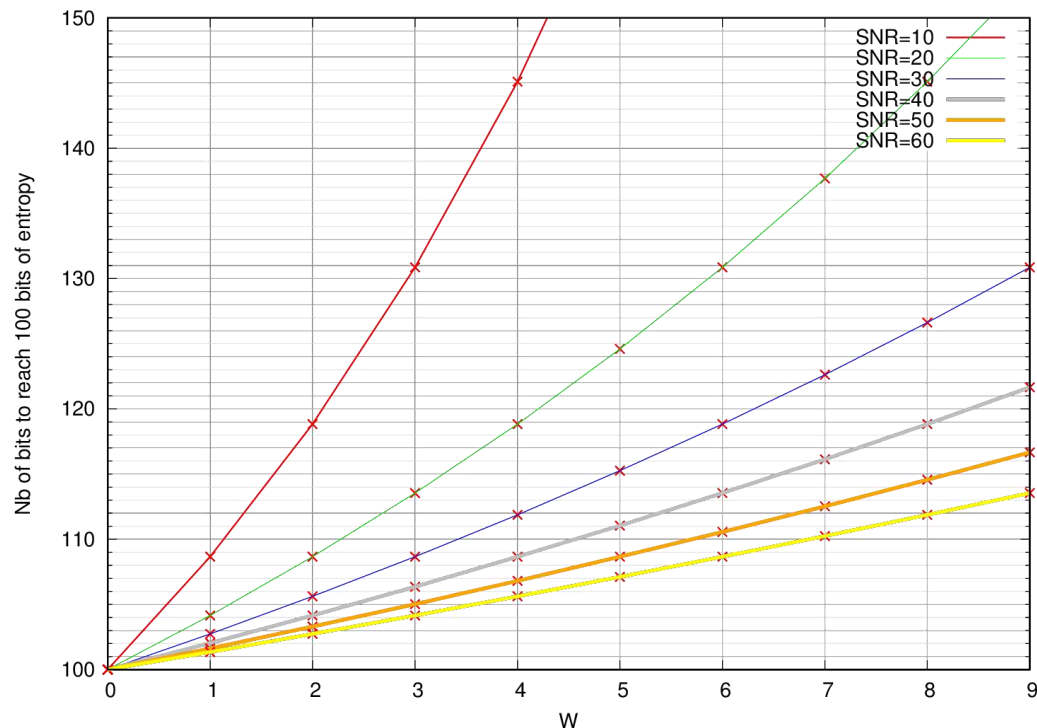
$$\widehat{BER}_{filt} = T\left(W, \frac{1}{SNR}\right) + \frac{1}{4} \operatorname{erf}\left(\frac{W}{\sqrt{2} \cdot SNR}\right) \left(\operatorname{erf}\left(\frac{W}{\sqrt{2}}\right) - 1\right)$$



Entropy after bit filtering

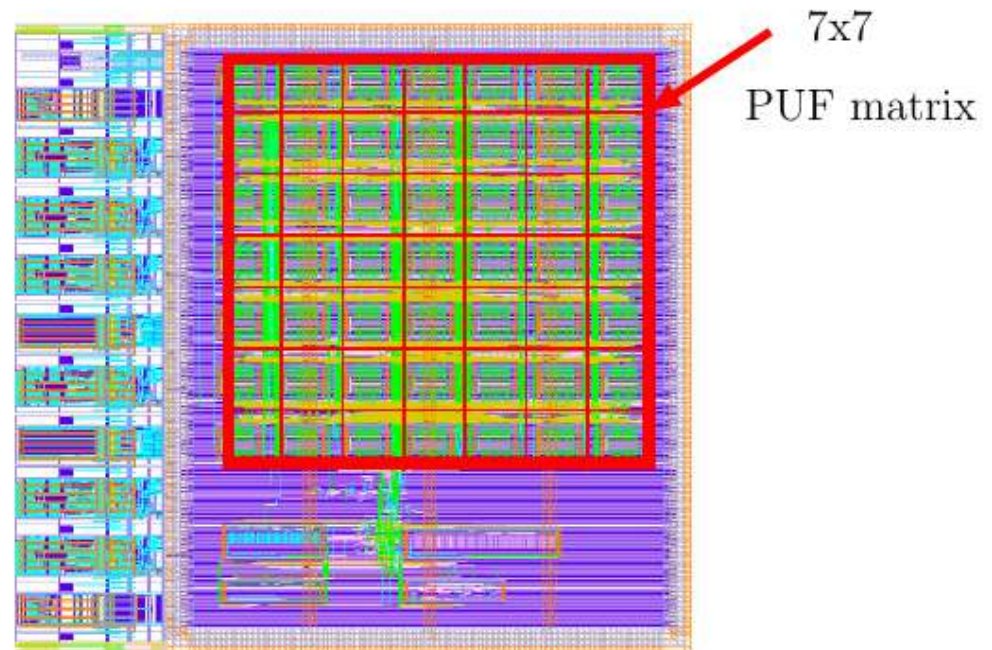
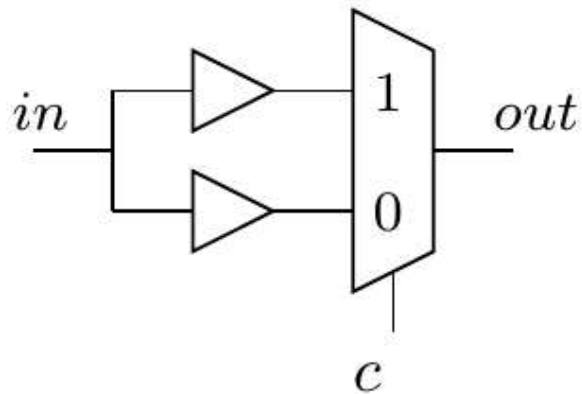
Number of delay elements to reach n bits of entropy with Hadamard codes

$$n' = \frac{n}{1 - \mathbb{P}(\text{Bit unreliable})} = \frac{n}{\text{erfc}\left(\frac{W}{SNR}\right)}$$



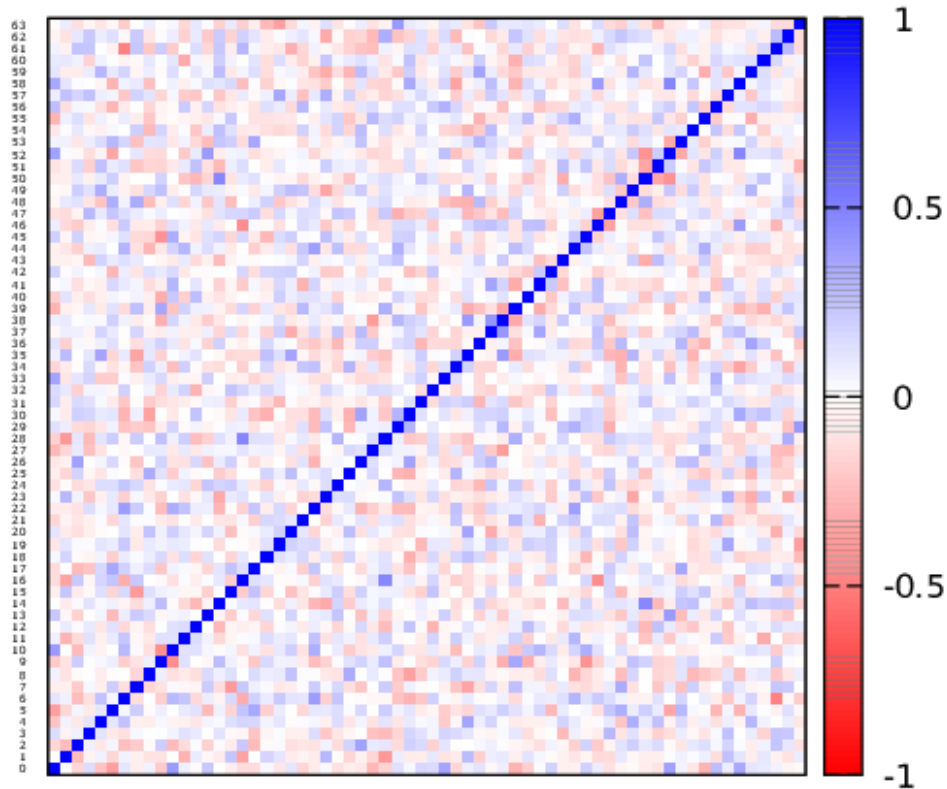
Results on real silicon

- n=54 cells, 65nm technology



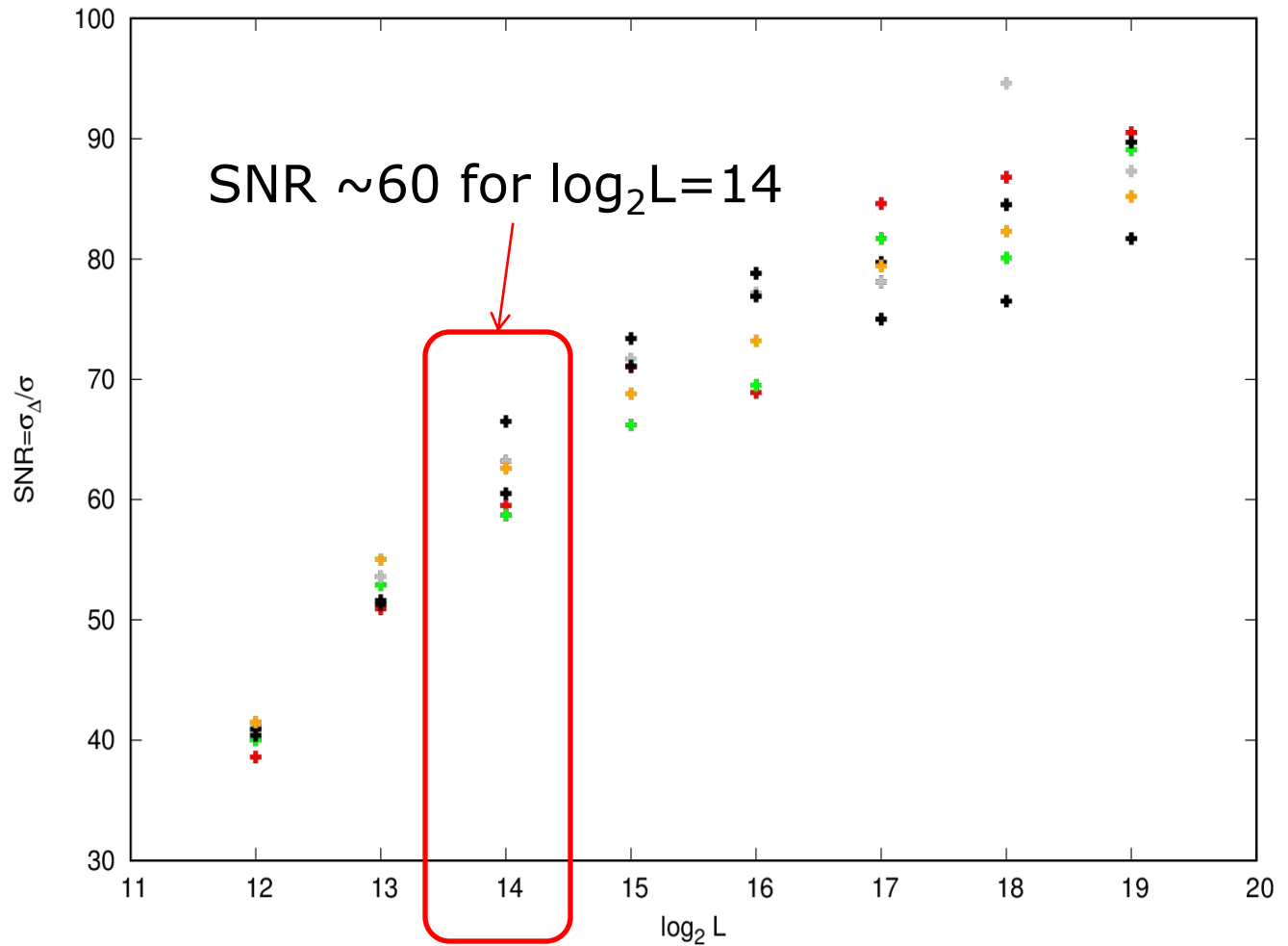
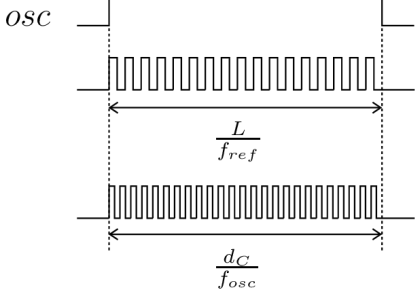
i..i.d. check

Correlation matrix on the 64 elements of the 49 PUFs

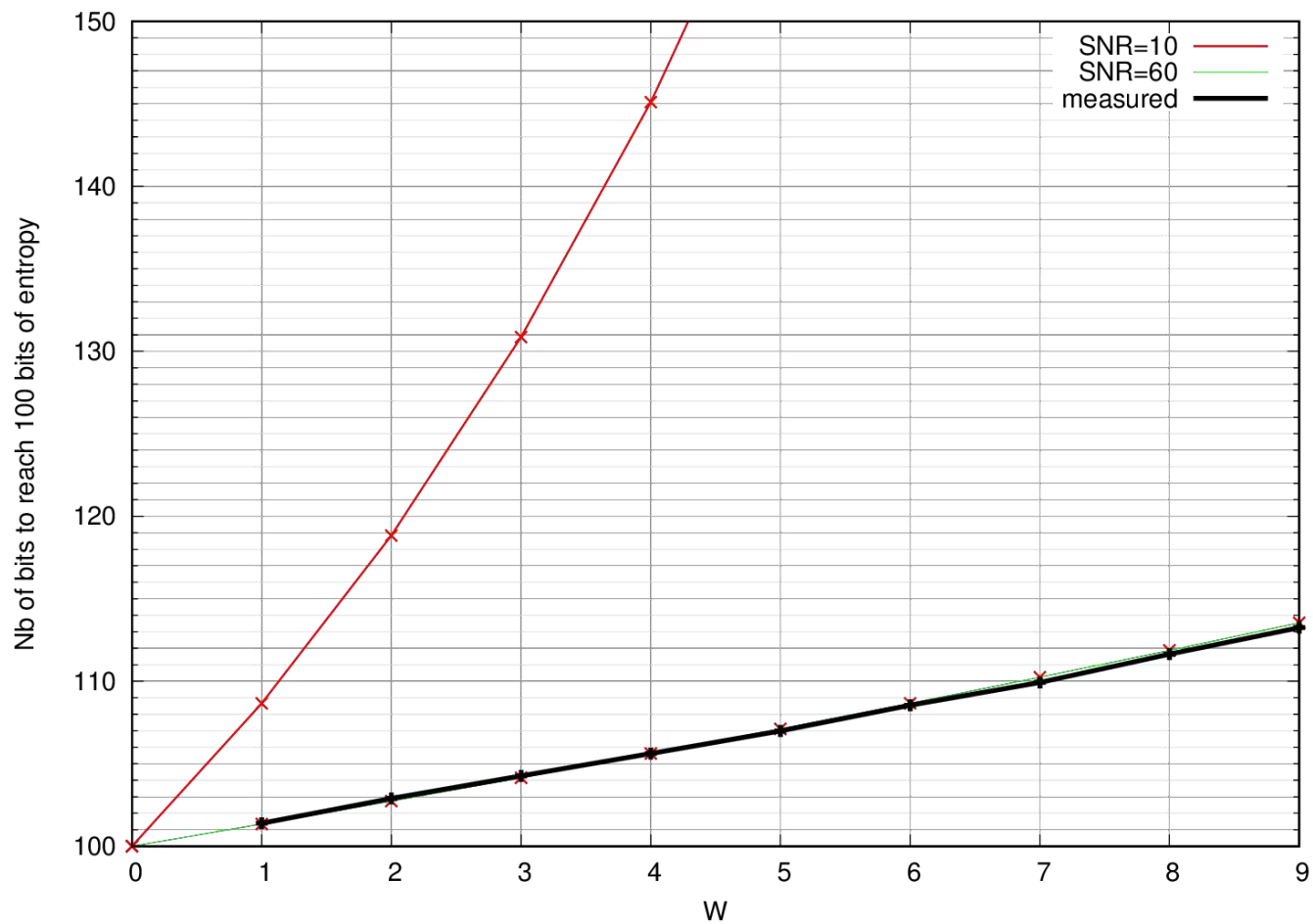


No correlation between the 64 delay elements
=> entropy ~ 64 with Hadamard codes

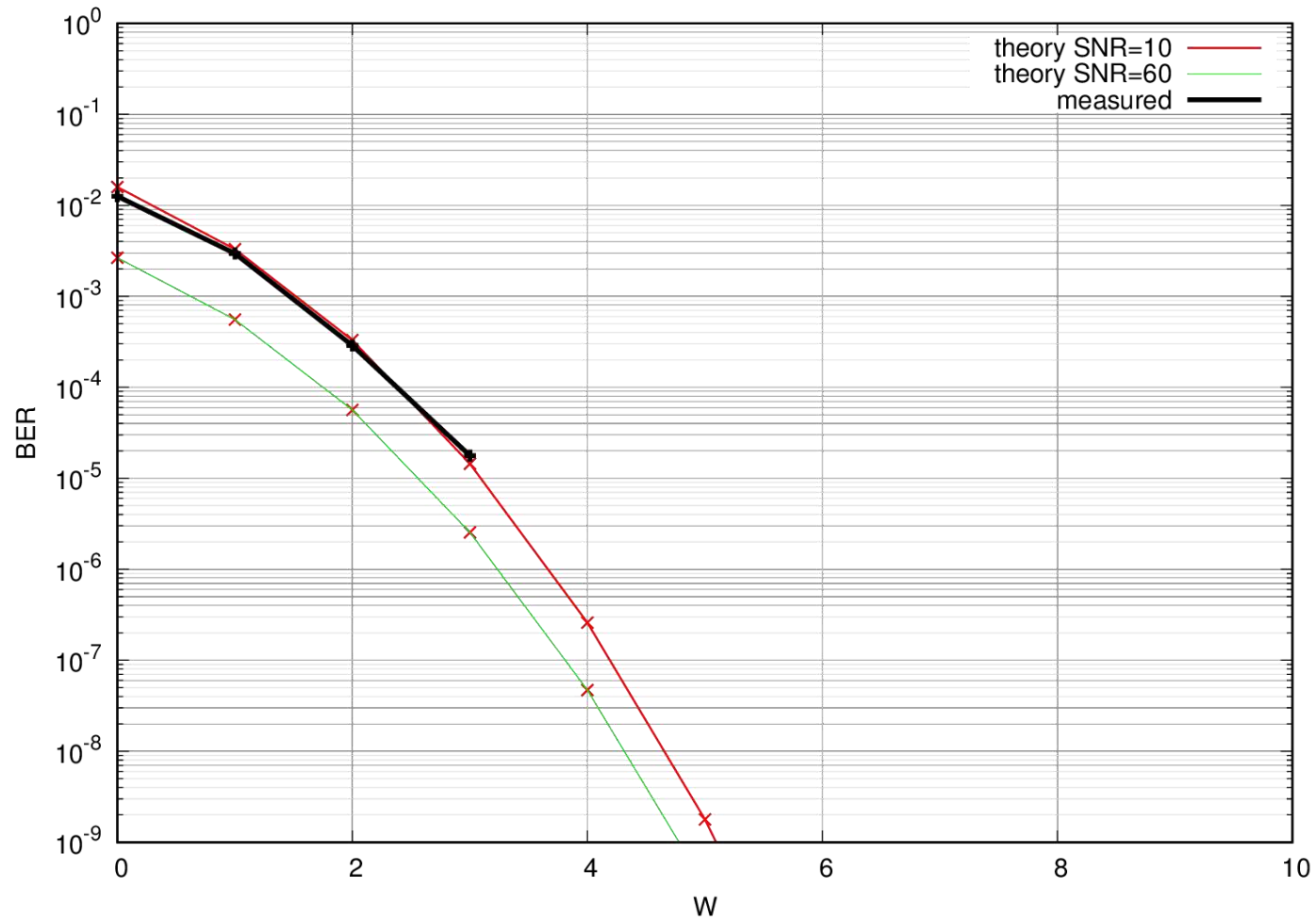
Impact of the measurement window on the SNR



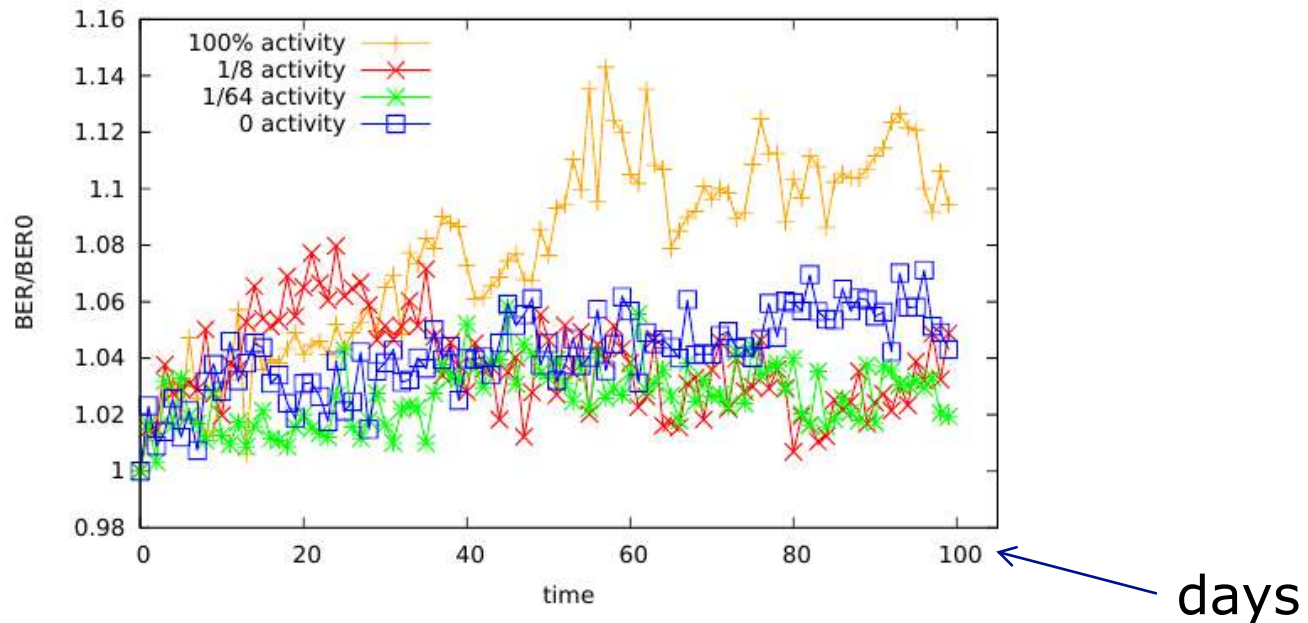
Entropy



Reliability: BER results



Aging Impact



Evolution of the BER of the Loop PUF after 100 days of accelerated aging. $T = 85^{\circ} \text{C}$, $V_{dd} = 2\text{v}$ (not 1v)

Conclusions

- ❑ **The Entropy of the Loop PUF can be formally obtained if Hadamard codes are used:**
 - Entropy = number of delay elements n N=Number of challenges
 - The entropy increases non linearly if $M > n$
- ❑ **The reliability of the Loop PUF is low (BER $\sim 10^{-3}$)**
- ❑ **It can be easily improved by exploiting the delay knowledge**
 - The unreliable bits are discarded
 - BER can go down 10^{-9}
 - But more bits are needed to reach the same entropy



THANK YOU
FOR YOUR ATTENTION